

Notice of References Cited	Application/Control No. 10/510,161	Applicant(s)/Patent Under Reexamination MIRBAHA ET AL.	
	Examiner SIMON D. NGUYEN	Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0039237	02-2003	FORSLOW, JAN E	370/352
*	B	US-6,937,566	08-2005	Forslow, Jan E.	370/231
*	C	US-2002/0101859	08-2002	Macleane, Ian B.	370/352
*	D	US-2002/0036983	03-2002	Widegren et al.	370/230.1
*	E	US-6,636,502	10-2003	Lager et al.	370/352
*	F	US-2003/0002507	01-2003	Hans et al.	370/393
*	G	US-2002/0196781	12-2002	Salovuori, Heikki	370/352
*	H	US-2005/0053068	03-2005	Toth et al.	370/390
*	I	US-2003/0043762	03-2003	Pang et al.	370/328
*	J	US-2003/0117993	06-2003	Syvanne et al.	370/349
*	K	US-2003/0043777	03-2003	Koponen et al.	370/349
*	L	US-2003/0152048	08-2003	Soininen et al.	370/328
*	M	US-2003/0156566	08-2003	Griswold et al.	370/338

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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